

Final Product/Process Change Notification

Document # : FPCN22647ZA Issue Date: 24 September 2019

Title of Change: Mold Compound Change attributed to an End of Life of Samsung SDI EMC for SuperFET propagation.		
Proposed Changed Material 24 September 2020 First Ship Date:		
Current Material Last Order Date:	30 May 2020 Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.	
Current Material Last Delivery Date:	23 September 2020 The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory.	
Product Category:	Active components – Discrete components	
Contact information: Contact your local ON Semiconductor Sales Office or < Peter.lee@onsemi.com >		
Samples:	Contact your local ON Semiconductor Sales Office to place sample order or < <u>PCN.samples@onsemi.com</u> > Sample requests are to be submitted no later than 45 days after publication of this change notification.	
Sample Availability Date:	31 October 2019 Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
PPAP Availability Date:	1 October 2019	
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or 	

Description and Purpose:

ON Semiconductor wishes to inform our customers of a change in mold compounds used for the devices listed in this PCN. This is the final product change notification (FPCN) of IPCN22647. This change is a result of an End of Life notification received from Samsung for several of their SDI Mold Compounds. Due to the discontinuance of the SDI mold compounds, ON Semiconductor will only have limited supplies of the existing material and in some cases this may not allow for the normal change notification period.

All other aspects of the impacted products (form, fit, function) will remain unchanged.

	Before Change Description	After Change Description
Mold compound	SL7300HFM, Supplier: Samsung SDI	KTMC1050GFA

There is no product marking change as a result of this change.

Reason / Motivation for	-	The motivation of change is to have better capacity support mass production
Change:	-	Late release from customer has potential supply issue.

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Anticipated impact on fit, form, function, reliability, product safety or manufacturability	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts.		
Sites Affected:	ON Semiconductor Sites: ON Suzhou, China	External Foundry/Subcon Sites: None	
Marking of Parts/ Traceability of Change:	I expire Parts from ON Semiconductor can be identified through product marking which i		

Reliability Data Summary:

:NVHL040N65S3F, FCH041N60F-F085 Device

RMS :<u>U59673,U56699</u>

PACKAGE: TO247

Test	Specification	Condition	Interval	Results
HTRB JESD22-A108		Ta = 150°C for device, bias = 100% of max rated	1008 hrs	0/231
HTGB JESD22-A108		Ta = 150°C for 1008 hours, 100% rated Vgs	1008 hrs	0/231
HTSL	JESD22-A103	Ta = 150°C for 1008 hours	1008 hrs	0/231
TC	JESD22-A104	Temp = -55°C to +150°C; for 1000 cycles	1000 cyc	0/231
IOL	IOL MIL STD750, M 1037 Ta=+25°C, delta Tj=100°C max, Ton=Toff is 3.5min		8572Cyc	0/231
HAST JESD22 A110		Temp= +110°C, RH=85% , 264hr, bias = 80% of rated BV or 100V max	264hrs	0/231
RSH	JESD22-B106	265 °C Immersion and 10s	10s	0/30
SD	J STD 002	Ta=245°C 5 sec dwell	5s	0/45
PD		Per Case Outline		0/30
Tri-temp		Tri-Temp Characterization, Per 48A		0/90
TR		Thermal Resistance		0/30
CDPA TCDT AEC Q101, rev D, test 7A (alt)		Custom Destructive Physical Analysis - TC Delamination Test, Post 1000 cyc TC		0/66
CDPA SAT	AEC-006	Post HTRB,HTGB		0/66
DPA	AEC-Q101-004 Section 4	Destructive Physical Analysis Post TC, HAST, HTRB, HTGB		0/6
CDPA WP BS	MIL 883E, AEC -006	Custom Destructive Physical Analysis - Wire Pull, Ball Shear Post TC, HTRB, HTGB		0/18
CDPA X Section	AEC -006	Post TC, HTRB, HTGB		0/9
Shift		Shift Analysis for HTRB/HTGB/HTSL/TC/IOL/HAST		Pass

NOTE: AEC-1pager is attached:

To view attachments:

- 1. Download pdf copy of the PCN to your computer
- 2. Open the downloaded pdf copy of the PCN
- 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field

4. Then click on the attached file/s

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Electrical Characteristic Sur

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the <u>PCN Customized Portal</u>.

Current Part Number	Qualification Vehicle
FCH041N60F-F085	FCH041N60F-F085
FCH041N65F-F085	FCH041N60F-F085
FCH077N65F-F085	FCH041N60F-F085
FCH104N60F-F085	FCH041N60F-F085
NVHL025N65S3	NVHL040N65S3F
NVHL027N65S3F	NVHL040N65S3F
NVHL040N65S3F	NVHL040N65S3F
NVHL072N65S3	NVHL040N65S3F
NVHL082N65S3F	NVHL040N65S3F
NVHL110N65S3F	NVHL040N65S3F

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Appendix A: Changed Products

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Product	Customer Part Number	New Part Number	Qualification Vehicle
FCH041N60F-F085		NA	FCH041N60F-F085
FCH041N65F-F085		NA	FCH041N60F-F085
FCH077N65F-F085		NA	FCH041N60F-F085
FCH104N60F-F085		NA	FCH041N60F-F085
NVHL027N65S3F		NA	NVHL040N65S3F
NVHL040N65S3F		NA	NVHL040N65S3F
NVHL072N65S3		NA	NVHL040N65S3F
NVHL110N65S3F		NA	NVHL040N65S3F